
ISPA 2007

***Downscaling of Finger Electrodes in 3-3 Fiber
Composite Transducers***



Fraunhofer Institut
Keramische Technologien
und Systeme

Andreas Schönecker

Wieland Beckert



SMART MATERIAL

Jan Kunzmann

Outline

- Introduction
- Modeling
- Experimental results
- Conclusions

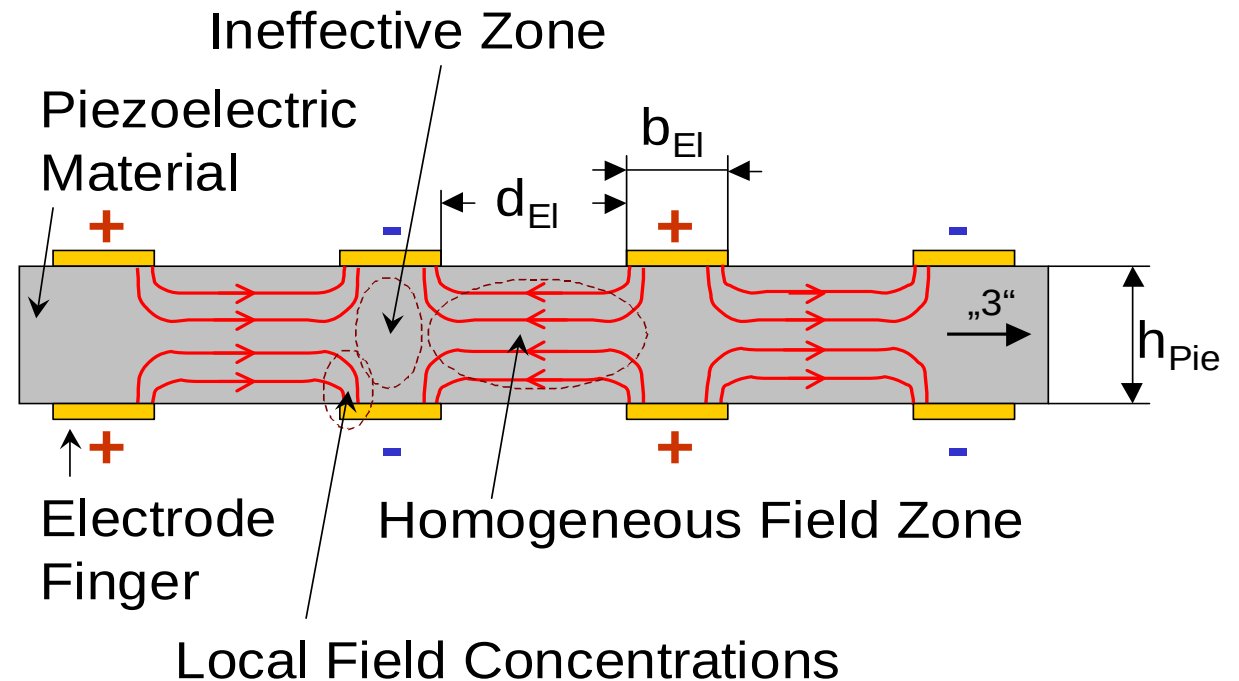
The problem

The IDE geometry,

- finger distance $d_{el} = 0,5\text{mm} \dots 1\text{mm}$
- driving voltages 1kV – 2 kV.
- limits industrial application due to systems incompatibility and cost

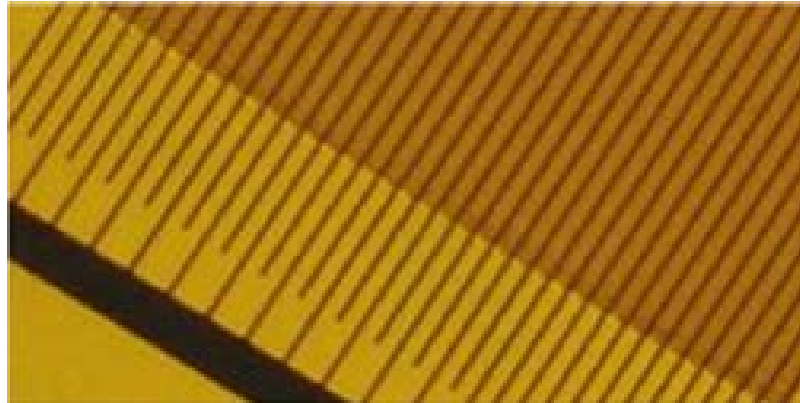
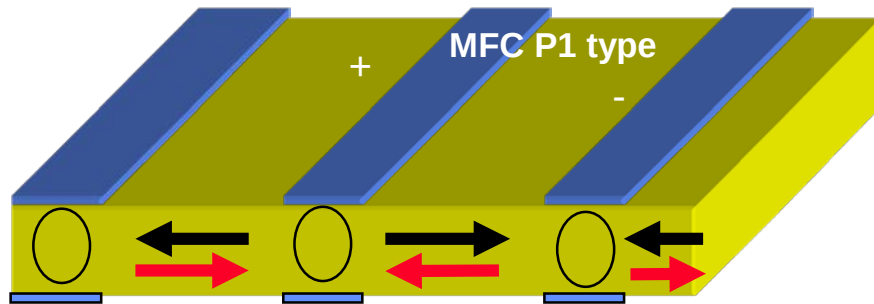
The issue

Can the driving voltage be reduced by down scaling the finger IDE geometry, still providing high efficiency and reliability of the device ?



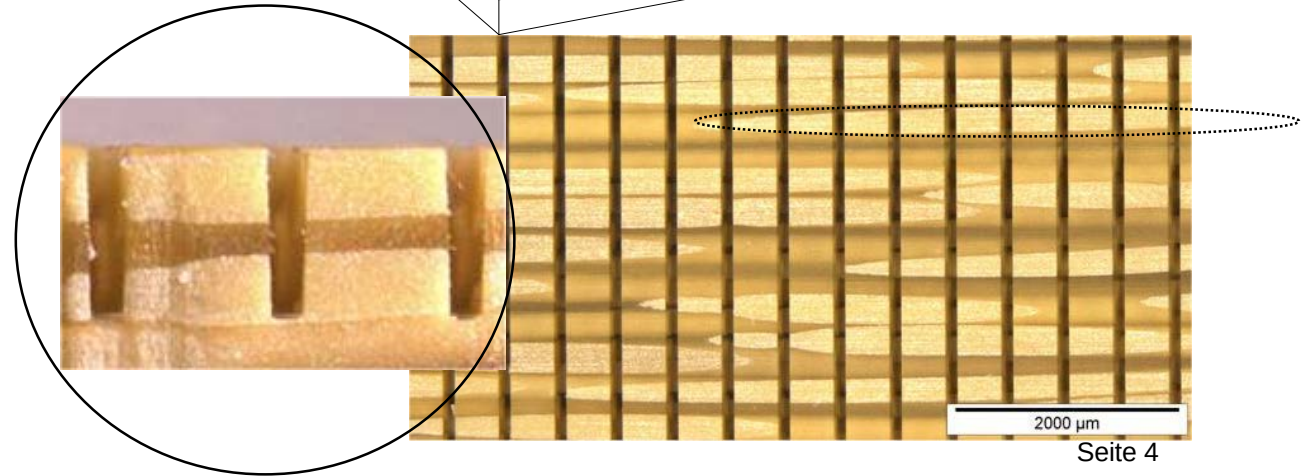
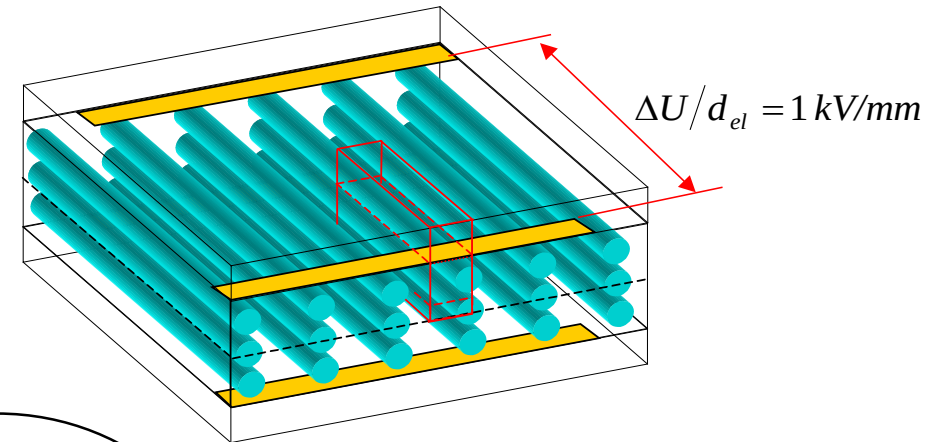
Considered Devices

Macro Fiber Composite (P1)



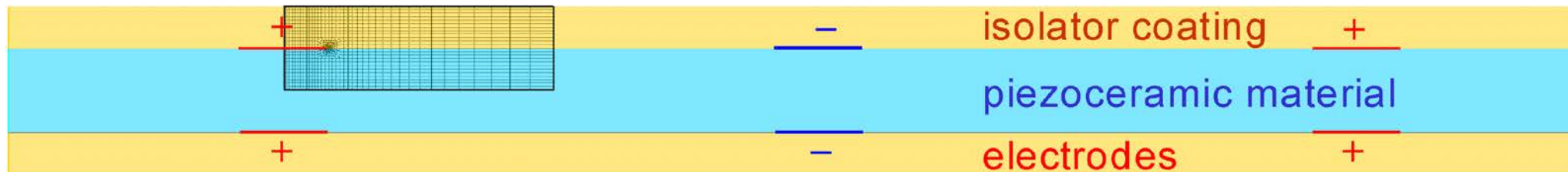
Archivierungsangaben

Smart Fiber Composite



Seite 4

Finite Element Model – Direct Metalization of PZT Fiber

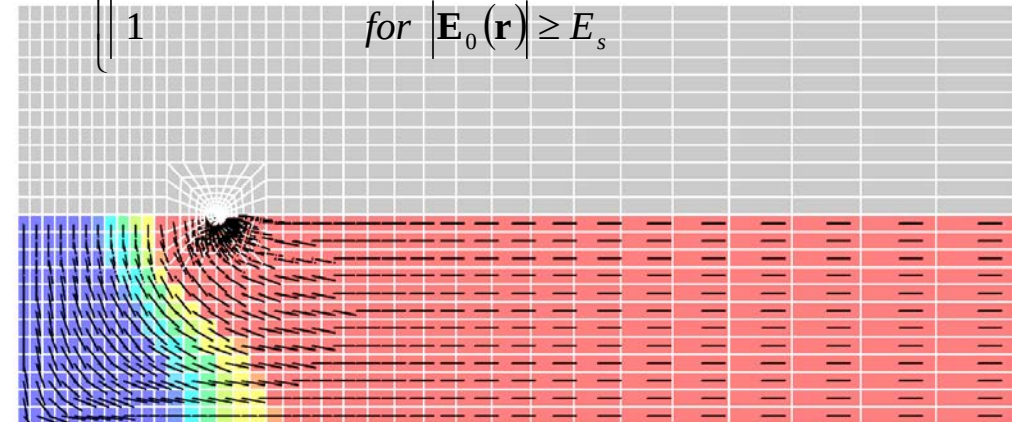
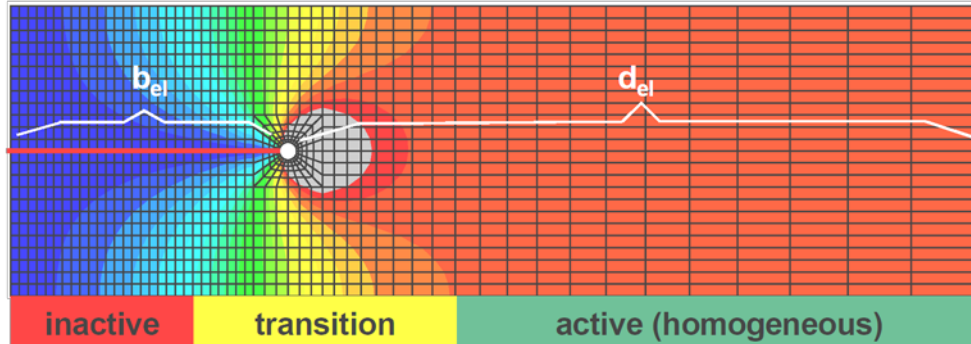


FEM using ANSYS

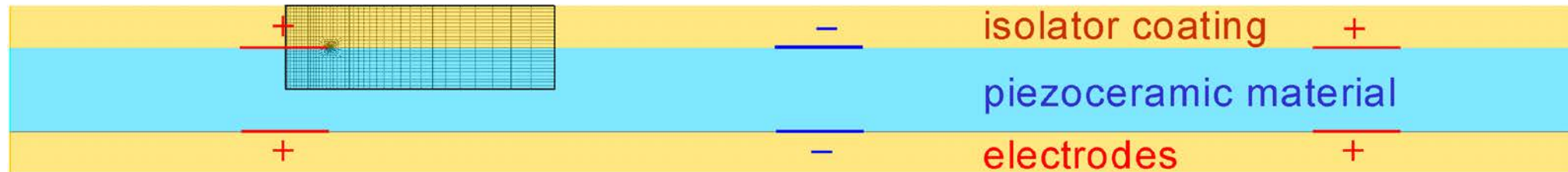
- three level polarization model

- poling direction $\mathbf{e}^p(\mathbf{r}) = \frac{\mathbf{E}_0(\mathbf{r})}{|\mathbf{E}_0(\mathbf{r})|}$

$$X(\mathbf{r}) = \begin{cases} 0 & \text{for } |\mathbf{E}_0(\mathbf{r})| < E_c \\ \frac{|\mathbf{E}_0(\mathbf{r})| - E_c}{E_s - E_c} & \text{for } E_c \leq |\mathbf{E}_0(\mathbf{r})| < E_s \\ 1 & \text{for } |\mathbf{E}_0(\mathbf{r})| \geq E_s \end{cases}$$



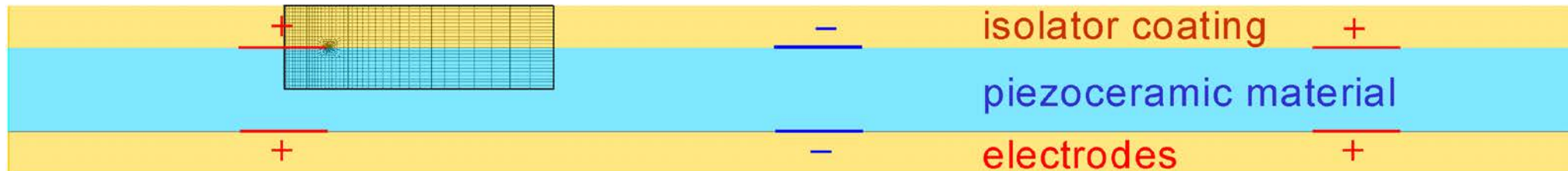
Finite Element Model – Consequences of IDE



Consequences of IDE

- Reduced active zone $d_{el} - 2 l_{tr}$
- Repeating $d_{el} + b_{el}$ length partly passive
- Scaled piezo module $C \cdot d_{33}$ accounting for the deformational constraint by the composite stack arrangement
- potential difference between neighbouring electrode fingers reduced by some voltage drop $\Delta U - 2 \Delta \phi$

Longitudinal Deformation



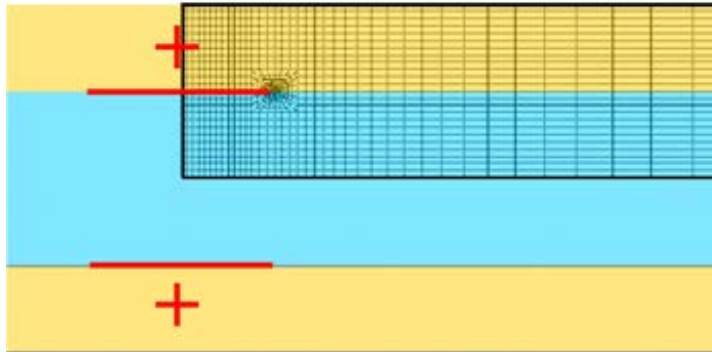
The maximum longitudinal deformation available from a layer arrangement with constant longitudinal electric field

$$\gamma_{\max} = -C \cdot d_{33} \cdot \frac{\Delta U}{d_{el}}$$

Longitudinal deformation with inhomogeneous electric field due to IDE electrodes

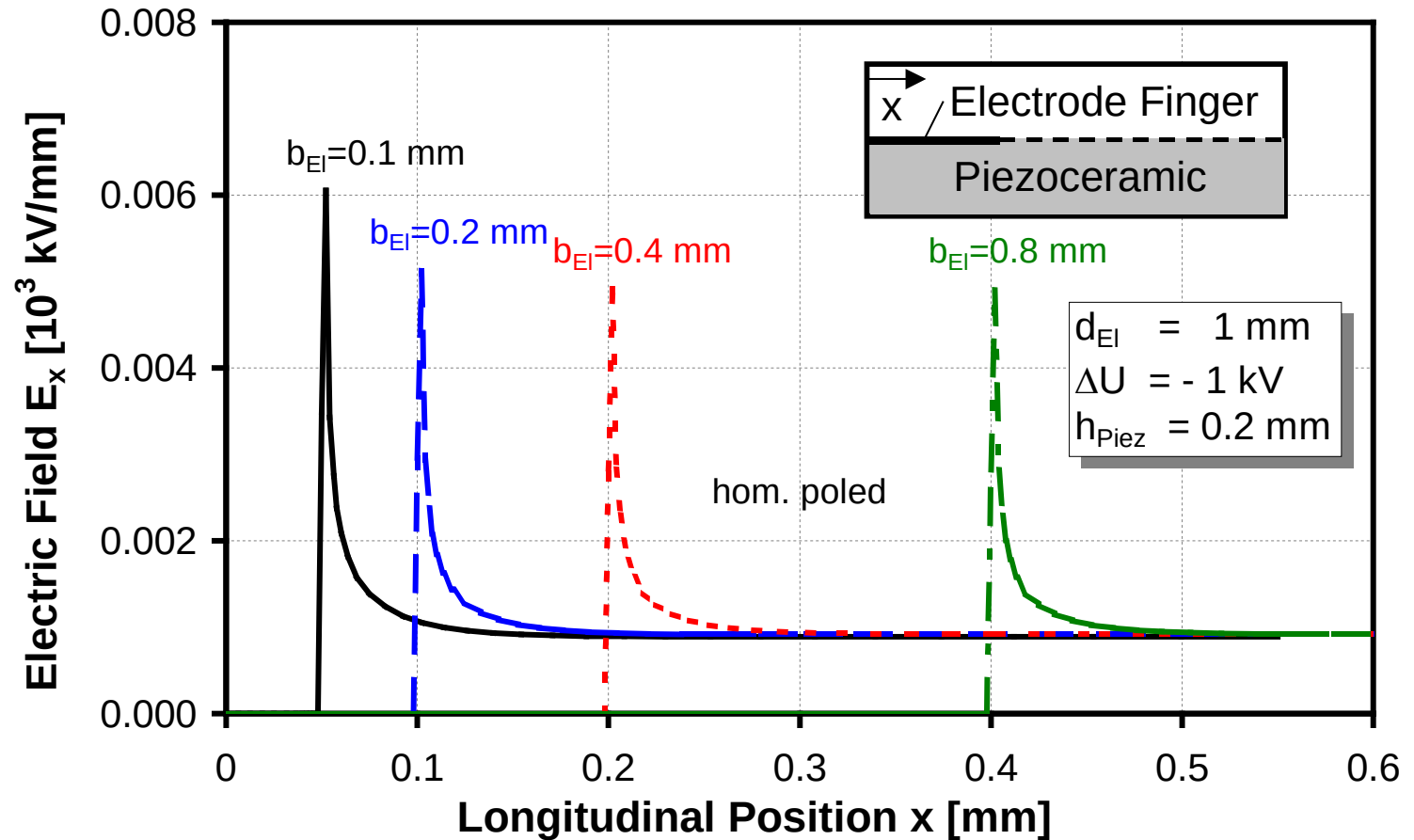
$$\gamma_{eff} = \frac{d_{el} - 2 \cdot l_{tr}}{d_{el} + b_{el}} \cdot C \cdot d_{33} \cdot \left(\frac{\Delta U - 2 \cdot \Delta \phi}{d_{el}} \right)$$

Local E- field concentrations, effect of finger width



Local field concentration E_x

- at finger edge .. 6 kV/mm
- field concentration zone 50 μm
- $U \rightarrow U - 2\phi$



Longitudinal Strain Performance

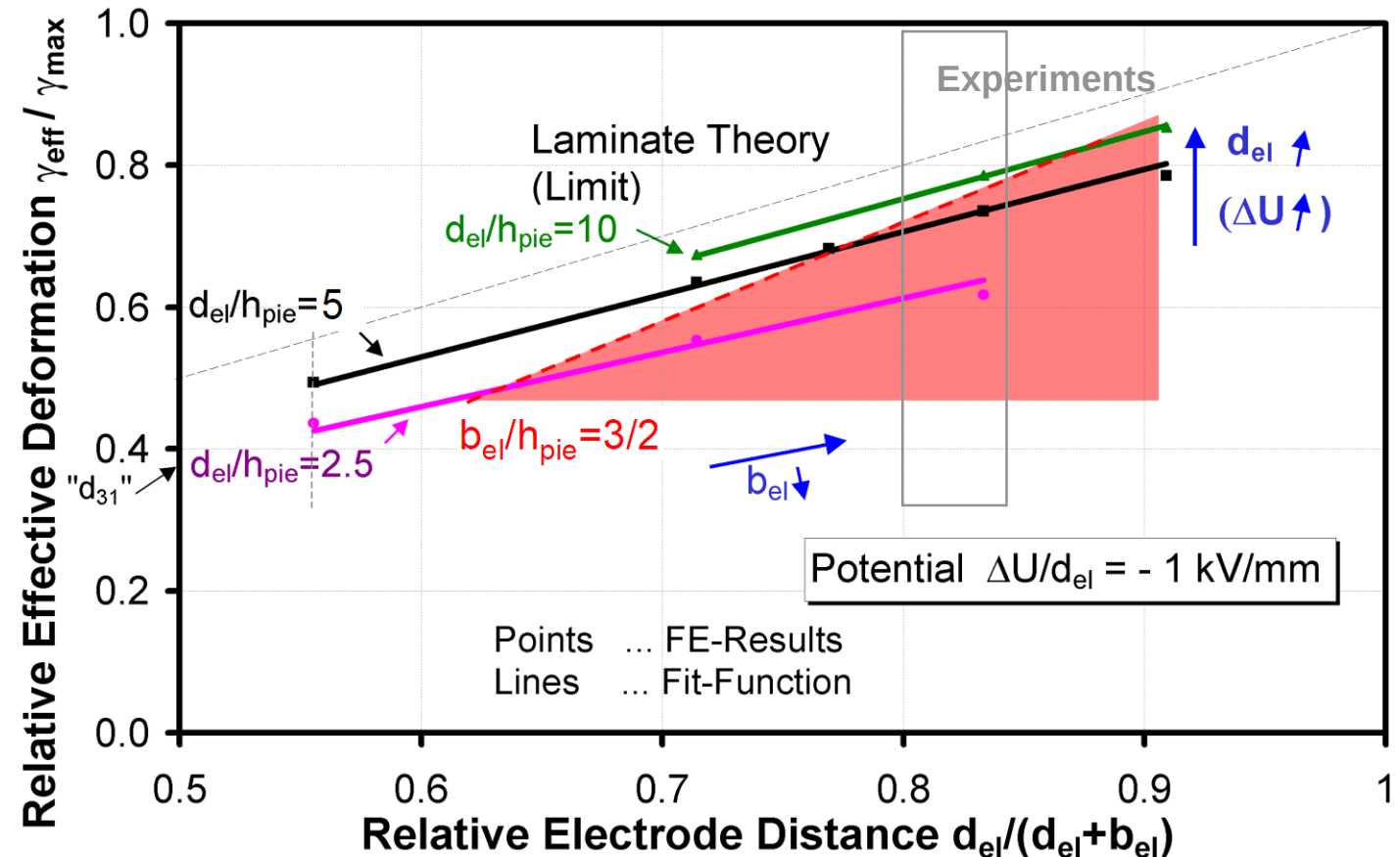
Increased Performance

- Increase the d/h ratio
- decrease the electrode finger width
- increase the electrode finger distance.

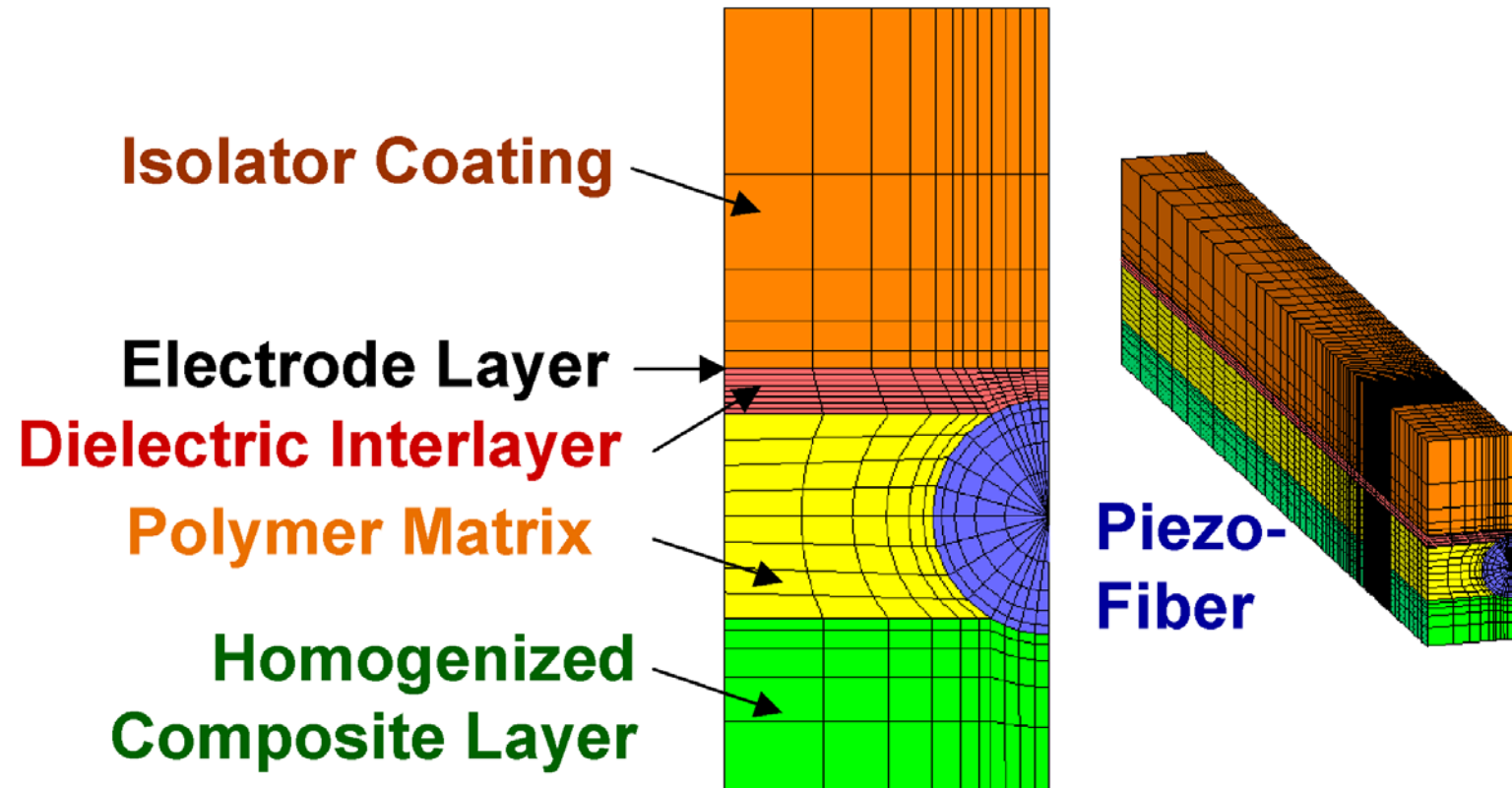
Restrictions

- Calculated field distributions show a saturation behaviour at
 $b \geq 1,5 h$
 $d \geq 4 h$
- Increasing the electrode distance d requires increase of the control voltage

Normalised Representation



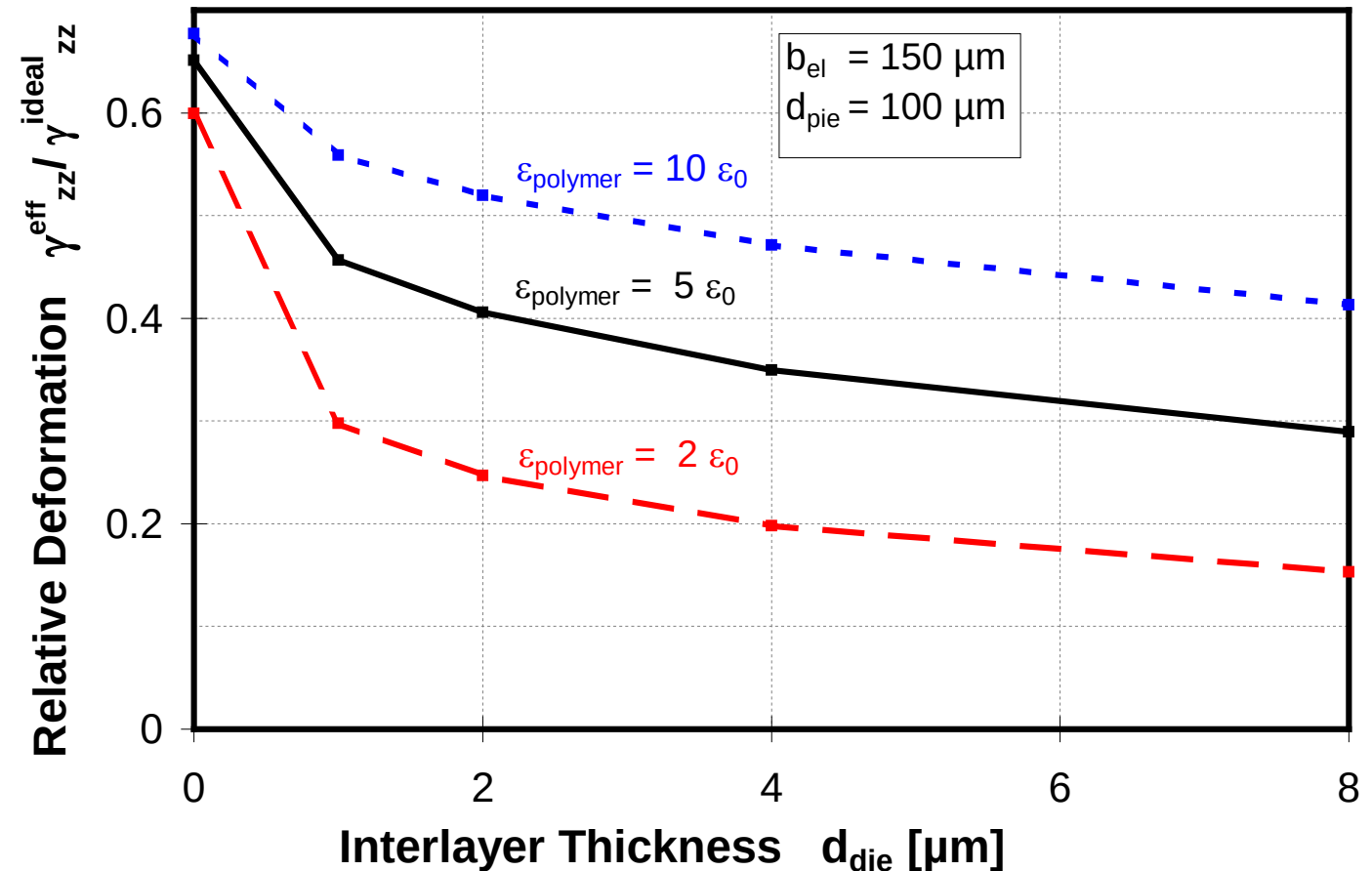
Finite Element Model – Effect of Dielectric Interlayer



Longitudinal Strain Performance – Effect of Dielectric Interlayer

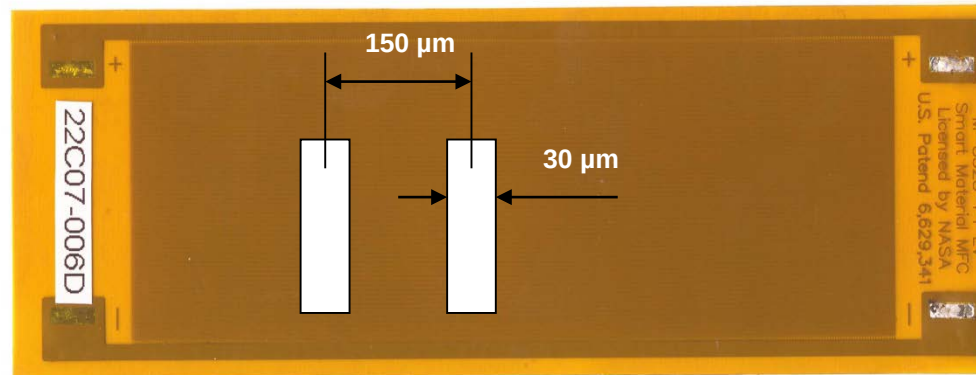
Local strain performance

- Reduced by dielectric interlayer
- Improved by the increase of permittivity of the dielectric interlayer



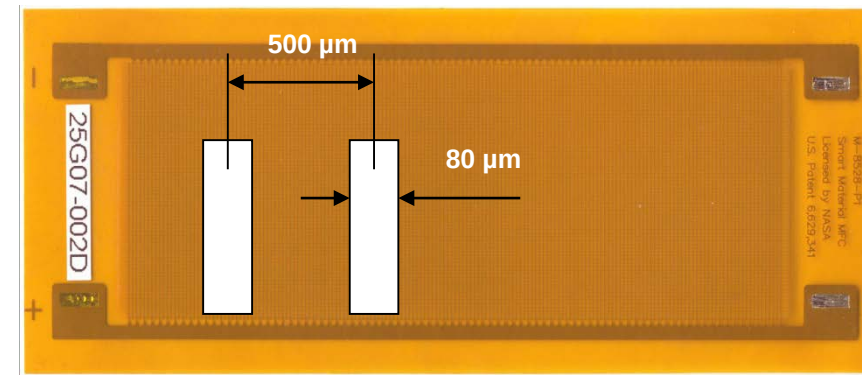
Test Samples

Low voltage 500 V
 $h = 180 \mu\text{m}, 100 \mu\text{m}$



$b/h = 0,17 \text{ \& } 0,30$
 $d/h = 0,67 \text{ \& } 1,20$

High voltage 1500 – 1800 V
 $h = 180 \mu\text{m}$



$b/h = 0,44$ --> $> 1,5$
 $d/h = 2,33$ --> > 4

Performance

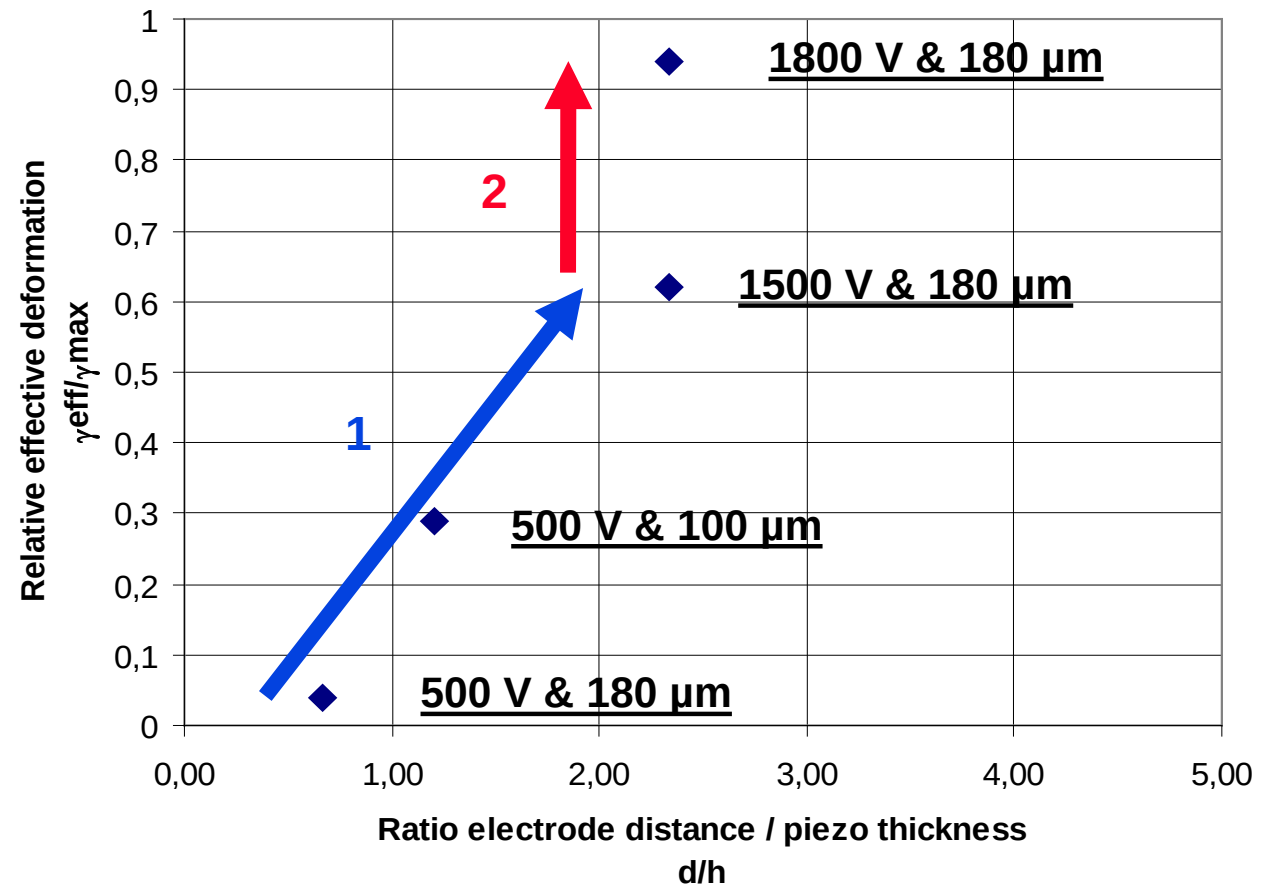
Increase of relative effective deformation by

1

homogenization of the electric field between the electrode edges

2

Increase of the electric field strength within the ceramic by compensation of the field drop at finger edges



Conclusions

- According to FEM modeling, high performance MFC require electrode distance d and finger width b related to PZT thickness h by the relations $d > 4 h$ and $d > 1,5 h$. This is due to electric field homogenization between the finger edges.
- E.g., Low driving voltages require downscaling of finger width b , finger distance d and ceramic thickness h , as well. Accordingly, the expected block force is reduced.
- A 500 V - MFC was prepared with $b=30\mu\text{m}$ / $d=120\mu\text{m}$ showing acceptable performance if the IDE was applied on $100\mu\text{m}$ PZT – fibers.
- Electric field drops at the finger edges and dielectric interlayers, which are found in MFC and SFC devices. This may be compensated by raised operation field strength $> 2 \text{ kV/mm}$.
- The calculated electric field gradient at the IDE edges approaches a few kV/mm . Devices should be investigated in this area in view of degradation and failure modes.